

### FQB5N80-VB Datasheet

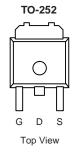
# N-Channel 800V (D-S)Super Junction Power MOSFET

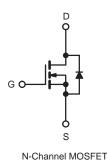
PRODUCT SUMMARY				
V <sub>DS</sub> (V)	800			
$R_{DS(on)}(\Omega)$	V <sub>GS</sub> = 10 V	1.2		
Q <sub>g</sub> (Max.) (nC)	200			
Q <sub>gs</sub> (nC)	24			
Q <sub>gd</sub> (nC)	110			
Configuration	Single			

#### **FEATURES**

- Dynamic dV/dt Rating
- Repetitive Avalanche Rated
- Isolated Central Mounting Hole
- · Fast Switching
- Ease of Paralleling
- Simple Drive Requirements
- Compliant to RoHS Directive 2002/95/EC







ABSOLUTE MAXIMUM RATINGS (T <sub>C</sub>	= 25 °C, unl	ess otherwis	se noted)			
PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			$V_{DS}$	800	V	
Gate-Source Voltage			$V_{GS}$	± 20	]	
Continuous Drain Current	V <sub>GS</sub> at 10 V	$T_{\rm C} = 25 ^{\circ}{\rm C}$ $T_{\rm C} = 100 ^{\circ}{\rm C}$	I <sub>D</sub>	5		
				3.9	Α	
Pulsed Drain Current <sup>a</sup>			I <sub>DM</sub>	21		
Linear Derating Factor				1.5	W/°C	
Single Pulse Avalanche Energy <sup>b</sup>			E <sub>AS</sub>	770	mJ	
Repetitive Avalanche Current <sup>a</sup>			I <sub>AR</sub>	7.8	Α	
Repetitive Avalanche Energy <sup>a</sup>			E <sub>AR</sub>	19	mJ	
Maximum Power Dissipation	T <sub>C</sub> = 25 °C			190	W	
Peak Diode Recovery dV/dt <sup>c</sup>	•		dV/dt	2.0	V/ns	
Operating Junction and Storage Temperature Range		T <sub>J</sub> , T <sub>stg</sub>	- 55 to + 150	°C		
Soldering Recommendations (Peak Temperature)	for	10 s	-	300 <sup>d</sup>		
Mounting Torque	6-32 or M3 screw			10	lbf ⋅ in	
				1.1	N · m	

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. V<sub>DD</sub> = 50 V, starting T<sub>J</sub> = 25 °C, L = 23 mH, R<sub>g</sub> = 25  $\Omega$ , I<sub>AS</sub> = 7.8 A (see fig. 12). c. I<sub>SD</sub>  $\leq$  7.8 A, dl/dt  $\leq$  140 A/ $\mu$ s, V<sub>DD</sub>  $\leq$  600 V, T<sub>J</sub>  $\leq$  150 °C.

<sup>\*</sup> Pb containing terminations are not RoHS compliant, exemptions may apply



THERMAL RESISTANCE RATINGS					
PARAMETER	SYMBOL	TYP.	MAX.	UNIT	
Maximum Junction-to-Ambient	R <sub>thJA</sub>	-	40		
Case-to-Sink, Flat, Greased Surface	R <sub>thCS</sub>	0.24	-	°C/W	
Maximum Junction-to-Case (Drain)	R <sub>thJC</sub>	-	0.65		

PARAMETER	SYMBOL	TES	T CONDITIONS	MIN.	TYP.	MAX.	UNIT
Static						•	
Drain-Source Breakdown Voltage	V <sub>DS</sub>	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		800	-	-	V
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference	e to 25 °C, I <sub>D</sub> = 1 mA	-	0.98	-	V/°C
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> :	= V <sub>GS</sub> , I <sub>D</sub> = 250 μA	2.0	-	4.0	V
Gate-Source Leakage	I <sub>GSS</sub>		V <sub>GS</sub> = ± 20 V		-	± 100	nA
Zero Gate Voltage Drain Current	I <sub>DSS</sub>		V <sub>DS</sub> = 800 V, V <sub>GS</sub> = 0 V		-	100	μΑ
			V, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 125 °C	-	-	500	<u> </u>
Drain-Source On-State Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V		-	1.2	-	Ω
Forward Transconductance	9fs	$V_{DS} = 100 \text{ V}, I_D = 3.7 \text{ A}^b$		5.6	-	_	S
Dynamic		<del></del>			I	1	1
Input Capacitance	C <sub>iss</sub>	$V_{GS} = 0 \text{ V},$ $V_{DS} = 25 \text{ V},$ $f = 1.0 \text{ MHz}, \text{ see fig. 5}$		-	3100	-	pF
Output Capacitance	C <sub>oss</sub>			-	800	-	
Reverse Transfer Capacitance	C <sub>rss</sub>			-	490	-	
Total Gate Charge	$Q_g$		I <sub>D</sub> = 3.8 A, V <sub>DS</sub> = 400 V, see fig. 6 and 13 <sup>b</sup>	-	-	200	nC
Gate-Source Charge	$Q_{gs}$	V <sub>GS</sub> = 10 V		-	-	24	
Gate-Drain Charge	$Q_{gd}$			-	-	110	
Turn-On Delay Time	t <sub>d(on)</sub>		V <sub>DD</sub> = 400 V, I <sub>D</sub> = 3.8 A,		19	-	- ns
Rise Time	t <sub>r</sub>	V <sub>DD</sub> =			38	-	
Turn-Off Delay Time	t <sub>d(off)</sub>	$R_g = 6.2 \ \Omega, R_D = 52 \ \Omega$ see fig. $10^b$		-	120	-	
Fall Time	t <sub>f</sub>			1	39	-	
Internal Drain Inductance	$L_{D}$	Between lead, 6 mm (0.25") from package and center of die contact		ı	5.0	-	
Internal Source Inductance	L <sub>S</sub>			-	13	-	- nH
Drain-Source Body Diode Characteristic	s					•	
Continuous Source-Drain Diode Current	I <sub>S</sub>	MOSFET symbol showing the integral reverse p - n junction diode		-	-	5.0	^
Pulsed Diode Forward Current <sup>a</sup>	I <sub>SM</sub>			-	-	21	- A
Body Diode Voltage	V <sub>SD</sub>	$T_J = 25  ^{\circ}\text{C},  I_S = 3.8  \text{A},  V_{GS} = 0  \text{V}^{\text{b}}$		-	-	1.8	V
Body Diode Reverse Recovery Time	t <sub>rr</sub>	T <sub>J</sub> = 25 °C, I <sub>F</sub> = 3.8 A, dl/dt = 100 A/μs <sup>b</sup>		-	650	980	ns
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>			-	3.8	5.7	μC
Forward Turn-On Time	t <sub>on</sub>	Intrinsic turn-on time is negligible (turn-or			ninated h	v Loand	12)

#### Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. Pulse width  $\leq$  300 µs; duty cycle  $\leq$  2 %.



#### TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

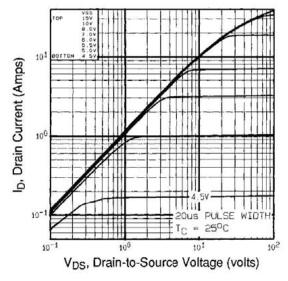


Fig. 1 - Typical Output Characteristics, T<sub>C</sub> = 25 °C

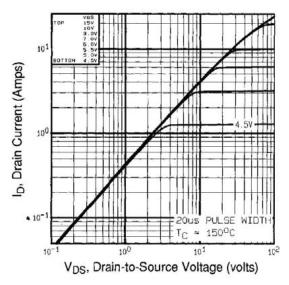


Fig. 2 - Typical Output Characteristics,  $T_C = 150$  °C

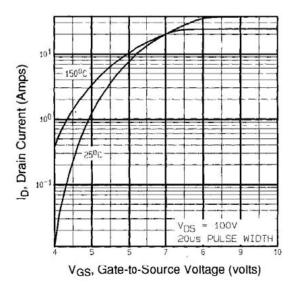


Fig. 3 - Typical Transfer Characteristics

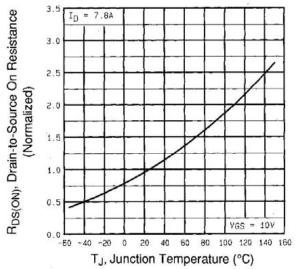


Fig. 4 - Normalized On-Resistance vs. Temperature



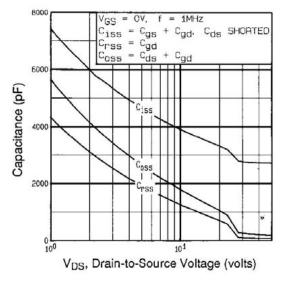


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

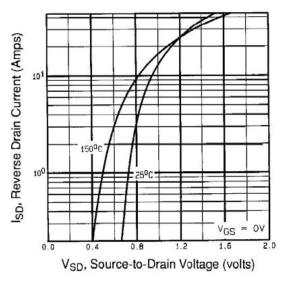


Fig. 7 - Typical Source-Drain Diode Forward Voltage

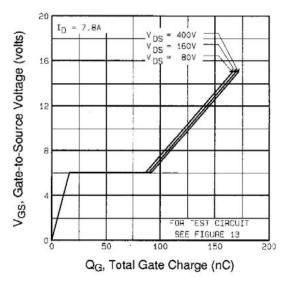


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

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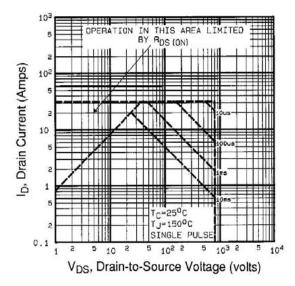


Fig. 8 - Maximum Safe Operating Area



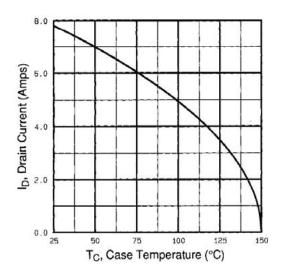


Fig. 9 - Maximum Drain Current vs. Case Temperature

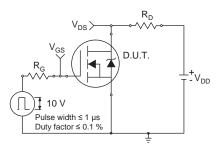


Fig. 10a - Switching Time Test Circuit

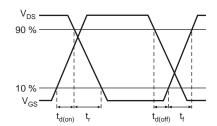


Fig. 10b - Switching Time Waveforms

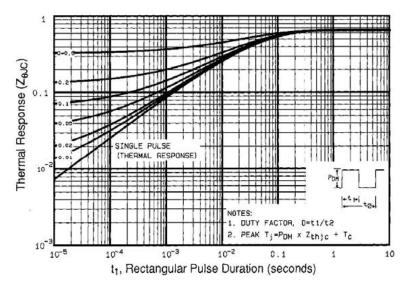


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case



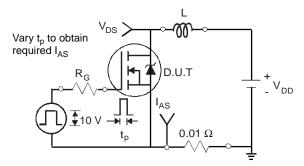


Fig. 12a - Unclamped Inductive Test Circuit

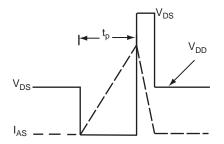


Fig. 12b - Unclamped Inductive Waveforms

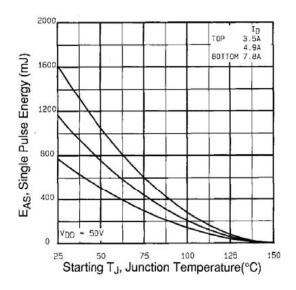


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

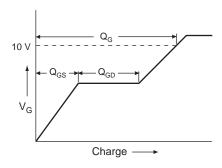


Fig. 13a - Basic Gate Charge Waveform

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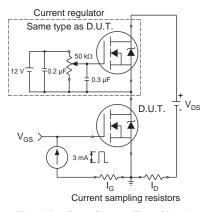
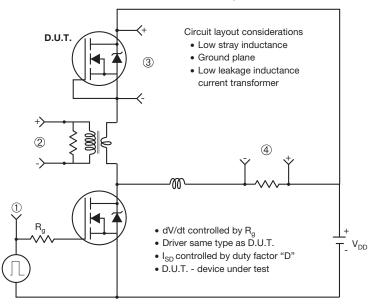


Fig. 13b - Gate Charge Test Circuit



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#### Peak Diode Recovery dV/dt Test Circuit



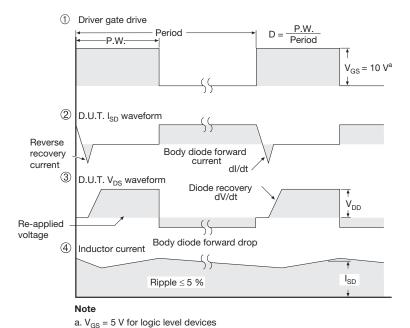


Fig. 14 - For N-Channel



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